

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/517,366	HATANAKA ET AL.	
Examiner	Art Unit	
Thao T. Tran	1711	

SEARCHED					
Class	Subclass	Date	Examiner		
428	423.1	9/29/2007	тт		
428	423.3	9/29/2007	TT		
428	424.7	9/29/2007	TT		
428	425.3	9/29/2007	TT		
428	473.5	9/29/2007	тт		
359	490	9/29/2007	TT		
359	485	9/29/2007	TT		
264	1.34	9/29/2007	TT		
252	585	9/29/2007	TT		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
359	490	9/29/2007	π		
264	1.34	9/29/2007	тт		
428	423.3	9/29/2007	TT		

SEARCH NOT (INCLUDING SEARCH	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
EAST, including inventor name search	9/29/2007	π			
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